

LIST OF ART CITED BY APPLICANT

(PTO-1449)

ATTY. DOCKET NO.
P-0616APPLN. SERIAL NO.
10/734,206

APPLICANT(S)

Seok II CHANG

FILING DATE
December 15, 2003GROUP
2611

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE

U.S. PATENT APPLICATION PUBLICATIONS

*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS

U.S. PATENT APPLICATIONS

*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
/FA/	JP 2001-501798	02/06/2001	Japan (English Abstract and claims and Japanese Full Text)			X	
/FA/	JP 2002-520922	07/09/2002	Japan (English Abstract and claims and Japanese Full Text)			X	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

	Japanese Office Action dated June 2, 2006.

EXAMINER

/Freshteh Aghdam/

DATE CONSIDERED

02/15/2007

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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**LIST OF PRIOR ART CITED BY
APPLICANT
(PTO-1449)**

ATTY. DOCKET NO.
P-0616

APPLN. SERIAL NO.
**New U.S. Patent
Application**

APPLICANT(S)
Se k II CHANG

FILING DATE
December 15, 2003

GROUP
N/A

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS.	SUBCLAS S	FILING DATE
/FA/	6,393,047	5/21/2002	Popovic'	375	140	6/15/1998

U.S. PATENT APPLICATION PUBLICATIONS

	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	

U.S. PATENT APPLICATIONS

	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No

OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

EXAMINER /Freshteh Aghdam/

DATE CONSIDERED 02/15/2007

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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ATTY. DOCKET NO.
P-0616

APPLN. SERIAL NO.
10/734,206

APPLICANT(S)

Seok Il CHANG

FILING DATE
December 15, 2003

GROUP **2631**

U.S. PATENT DOCUMENTS

[illegible]

U.S. PATENT APPLICATION PUBLICATIONS

	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	

U.S. PATENT APPLICATIONS

	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	
IFA	US 2002/0012403	01/31/2002	McGowan et al.	375	295	

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
FA	EP 0 716 529 A2	06/12/1996	Europe			X	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

Copy of European Search Report.

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DATE CONSIDERED

02/15/2007

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